EXICOR® GEN SERIES



PRODUCT BULLETIN



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Ultra-low retardation measurements. Award Winning. Reliable.



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Applications

- Quality control metrology
- Low-level birefringence measurements of
 - Display glass
 - LCD
 - Large irregular shaped planar glass and plastic
 - Plastic film

System Options

- Scan In Motion (SIM)
- Keep Out Barrier
- Manual or Auto Tilt Stage
- Thickness and Warpage Sensors on GEN5 or GEN6

Significant Features

- Unprecedented sensitivity in low-level birefringence measurement
- Simultaneous measurement of birefringence magnitude and angle
- Precision repeatability
- High-speed measurement
- No moving parts in the optical system
- Automatic mapping of variable-sized optical elements
- Photoelastic modulator technology
- Simple, user-friendly operation



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GEN Specifications

GEN5 GEN6 GEN9

Retardation Range 0.005nm to 300 nm

Resolution¹ 0.001 nm

Repeatability¹ ± 0.01 nm (Retardation < 1 nm) or \pm 1% (Retardation > 1 nm)

Angular Resolution/Repeatability $0.01^{\circ}/\pm0.05^{\circ}$ Measurement Time Up to 10 pps Wavelength 632.8 nm Spot size \sim 1 mm typical

Demodulation Analysis Technique Hinds Instruments Signaloc[™] Lock-in Amplifiers

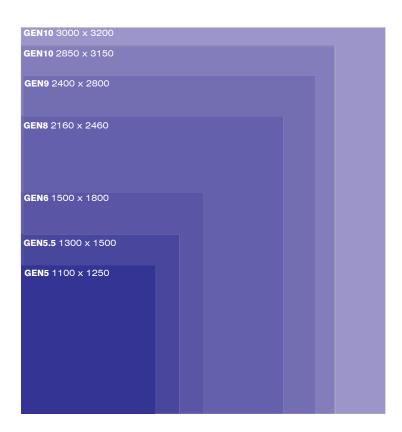
Measurement Units nm (retardation), ° (angle)

 Maximum Sample Size (mm)
 1175 x 1375
 1600 x 2000
 2500 x 3000

 Maximum Scan Area (mm)
 1100 x 1300
 1575 x 1925
 2400 x 2800

GEN System Glass Measurements

GENERATION	GLASS SIZE
5	1100 x 1250
	1100 x 1300
5.5	1300 x 1500
6	1500 x 1850
8	2160 x 2450
	2200 x 2500
9	2400 x 2800
10	2580 x 3050
	3000 x 3200



¹ Typical performance at 5nm Retardation

² Maximum data collection speed. Sample XY scan time dependent on stage movement parameters.

³ Custom wavelengths available